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	Document ID	Kind Codes	Source	Issue Date	Pa
1	US 20030117842		US-PGPU	20030626	59
2	US 20020093032		US-PGPU	20020718	59
3	US 6680867 B2		USPAT	20040120	55
4	US 6563743 B2		USPAT	20030513	57

US 6563743 B2

(1) United States Patent
Hanzawa et al.

(1) Patent No.: US 6,563,743 B2
(1) Date of Patent: May 13, 2003

(1) BACKGROUND OF THE INVENTION
The present invention relates to a semiconductor device having a plurality of memory cells and a redundancy circuit for detecting a defective memory cell.

(2) FIELD OF THE INVENTION
The present invention relates to a semiconductor device having a plurality of memory cells and a redundancy circuit for detecting a defective memory cell.

(3) BRIEF SUMMARY OF THE INVENTION
The present invention provides a semiconductor device having a plurality of memory cells and a redundancy circuit for detecting a defective memory cell.

(4) BRIEF DESCRIPTION OF THE DRAWINGS
FIG. 1 is a block diagram of a semiconductor device according to the present invention.

(5) DETAILED DESCRIPTION OF THE INVENTION
The present invention provides a semiconductor device having a plurality of memory cells and a redundancy circuit for detecting a defective memory cell.

(6) CLAIMS
What is claimed is:

(7) REFERENCE NUMERALS
1: Memory cell array
2: Redundancy circuit
3: Control circuit
4: Address decoder
5: Data bus
6: Word line driver
7: Bit line driver
8: Sense amplifier
9: Memory cell array
10: Redundancy circuit
11: Control circuit
12: Address decoder
13: Data bus
14: Word line driver
15: Bit line driver
16: Sense amplifier

(8) OTHER PUBLICATIONS
U.S. Pat. No. 6,563,743 B2, Hanzawa et al., filed May 13, 2003.

(9) ABSTRACT
A semiconductor device having a plurality of memory cells and a redundancy circuit for detecting a defective memory cell.

(10) DRAWING FIGURES
FIG. 1 is a block diagram of a semiconductor device according to the present invention.